2:30 D-22 **Crystal Structures of $BaSrR_4Zn_2O_{10}$, R = La, Nd, Sm, Eu**

J.A. Kaduk, *Poly Crystallography, Naperville, IL*
W. Wong-Ng, *NIST, Gaithersburg, MD*

2:50 D-60 **Detection and Quantification of Passivation Layers in Electrochemical Inert Anodes by In-Situ and Ex-Situ Diffraction**

M.R. Rowles, K. McGregor, G.A. Snook, *CSIRO Process Science and Engineering/CSIRO Light Metals Flagship, Victoria, Australia*
I.C. Madsen, N.V.Y. Scarlett, M. Lanyon, A. Urban, *CSIRO Process Science and Engineering, Victoria, Australia*
M.J. Styles, D.P. Riley, *The University of Melbourne, Victoria, Australia*

3:10 **Break**

3:40 C-6 **Characterization of X-ray Powder Diffraction Data of $Ba_xSr_{1-x}SO_4$ ($0 \leq x \leq 1$) by Rietveld Refinement**

S.R. Zaidi, H. Sitepu, S. Shen, N. Al-Yami, *Saudi ARAMCO, Dhahran, Saudi Arabia*

4:00 D-77 **XRD Anisotropic Broadening of Nano-Particles**

Y. Wang, S.L.I. Chan, Y.R. Shen, R. Amal, K. Kiatkittipong, *University of New South Wales, Australia*

4:20 D-19 **Differences between Near-Surface and Bulk Preferred Orientation with Powder Diffraction Data of Molybdite (MoO_3) and Calcite ($CaCO_3$)**

H. Sitepu, *Curtin University of Technology, Perth, Australia and Saudi ARAMCO, Dhahran, Saudi Arabia*
B.H. O'Connor, D. Li, *Curtin University of Technology, Perth, Australia*

4:40 D-13 **Computational Texture Analysis with MTEX**

R. Hielscher, *Technische Universitaet Chemnitz, Germany*
F. Bachmann, H. Schaeben, *Technische Universitaet Bergakademie Freiberg, Germany*

THURSDAY PM

XRD

MICRO DIFFRACTION — EVERGREEN D

Chair: **C. Murray**, IBM, T.J. Watson Research Center, Yorktown Heights, NY

2:00 D-20 ***Invited*—Three Dimensional X-ray Diffraction Microscopy**

L. Margulies, *Brookhaven National Laboratory, Upton, NY*
H.F. Poulsen, S. Schmidt, D.J. Jensen, *Risoe National Lab, Roskilde, Denmark*
G. Vaughan, J. Wright, *ESRF, Grenoble, France*

2:30 D-30 ***Invited*—Nanoscale Scanning Probe Diffraction Microscopy at the Hard X-ray Nanoprobe Beamline**

M. Holt, S. Hruszkewycz, R. Winarski, V. Rose, J. Maser, *Argonne National Laboratory, Argonne, IL*

3:00 D-81 **Multi-Dimensional X-ray Investigation of Materials—Ranging from Classical Bragg-Brentano Type Diffraction Phase Analysis to 3 Dimensional CT Microstructure Analysis**

H. Pöllmann, *University of Halle/Mineralogy, Halle, Germany*
R. Maier, U. Riedl, G. Blaj, *PANalytical, Almelo, The Netherlands*

https://doi.org/10.1154/1.3455009 Published online by Cambridge University Press